VDS

RDS(on),typ VGS=10V

RDS(on),typ VGS=4.5V

ID

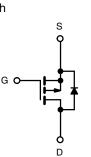
P-Channel 30-V (D-S) MOSFET

FEATURES

- Trench power MOSFET
- 100 % R_g and UIS tested

APPLICATIONS

- Notebook battery charging
- Notebook adapter switch



P-Channel MOSFET

PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	-30	V	
Gate-Source Voltage		V _{GS}	± 25	v	
	T _C = 25 °C		-30 ^d		
Continuous Durin Current (T. 150 °C)	T _C = 70 °C		-25 ^d		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	-13.9 ^{a, b}		
	T _A = 70 °C		-11.1 ^{a, b}	<u>^</u>	
Pulsed Drain Current		I _{DM}	-120	— A	
	T _C = 25 °C		-35 d		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	_3 a, b		
Avalanche Current		I _{AS}	-29		
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	42	mJ	
	T _C = 25 °C		52		
Mauianan Davies Diagingtian	T _C = 70 °C		33	w	
Maximum Power Dissipation	T _A = 25 °C	P _D	3.7 ^{a, b}	vv	
	T _A = 70 °C		2.4 ^{a, b}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +150	**	
Soldering Recommendations (Peak Temperature) e, f	1 1	260			

THERMAL RESISTANCE RATINGS							
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT		
Maximum Junction-to-Ambient a, c	t ≤ 10 s	R _{thJA}	26	33	°C/W		
Maximum Junction-to-Case	Steady State	R _{thJC}	1.9	2.4	C/W		

Notes

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under steady state conditions is 81 °C/W.
- d. Package limited.
- e. The DFN 3 x 3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- f. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.

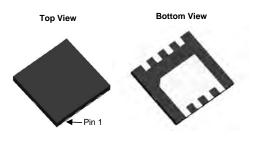
g. Based on T_C = 25 °C.

RoHS COMPLIANT HALOGEN

FREE

1





DFN 3x3 EP

V

mΩ

mΩ

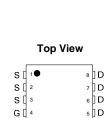
А

-30

9

17

-30



VBQF2311

PARAMETER	SYMBOL	erwise noted) TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
	STMBOL	TEST CONDITIONS	MIIN.	TTP.	MAX.	UNIT	
Static				T			
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = -250 μA	-30	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = -250 μA	-	-25	-	mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		-	4.7	-		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = -250 \ \mu A$	-1.2	-	-2.5	V	
Gate-Source Leakage	I _{GSS}	V_{DS} = 0 V, V_{GS} = ± 25 V	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	-1	μA	
	.033	V_{DS} = -30 V, V_{GS} = 0 V, T_J = 55 $^\circ C$		-	-5	μ, ι	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge$ -10 V, $V_{GS} =$ -10 V	-30	-	-	A	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = -10 \text{ V}, \text{ I}_{D} = -13.9 \text{ A}$	-	9	-	mΩ	
Brain obdice on otale nesistance		$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -10.3 \text{ A}$	-	17	-		
Forward Transconductance ^a	9 _{fs}	V _{DS} = -15 V, I _D = -13.9 A	-	35	-	S	
Dynamic ^b							
Input Capacitance	Ciss		-	1800	-	pF	
Output Capacitance	C _{oss}	V _{DS} = -15 V, V _{GS} = 0 V, f = 1 MHz	-	370	-		
Reverse Transfer Capacitance	C _{rss}		-	312	-		
	-	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -13.9 \text{ A}$	_	-	15	nC	
Total Gate Charge	Q_g		_	-	13		
Gate-Source Charge	Q _{gs}	V _{DS} = -15 V, V _{GS} = -4.5 V, I _D = -13.9 A	-	_	6		
Gate-Drain Charge	Q _{gd}		-	-	11		
Gate Resistance	R _q	f = 1 MHz	0.4	2	4	Ω	
Turn-On Delay Time	t _{d(on)}		-	11	22		
Rise Time	t _r	$V_{DD} = -15 \text{ V}, \text{ R}_{\text{I}} = 1.35 \Omega$	-	9	18		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -11.1 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$	-	32	50		
Fall Time	t _f		-	9	18		
Turn-On Delay Time	t _{d(on)}		_	40	60	ns	
Rise Time	t _r	- V _{DD} = -15 V, R _I = 1.35 Ω	-	43	65	-	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -11.1 \text{ A}, V_{\text{GEN}} = -4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$	-	30	45		
Fall Time	t _f			11	22		
Drain-Source Body Diode Characteris	· ·		-	<u> </u>	~~~	I	
Continuous Source-Drain Diode	5003						
Current	I _S	T _C = 25 °C	-	-	-35	А	
Pulse Diode Forward Current	I _{SM}		-	-	-60		
Body Diode Voltage	V _{SD}	I _S = -11.1 A, V _{GS} = 0 V	-	-0.8	-1.2	V	
Body Diode Reverse Recovery Time	t _{rr}		-	33	50	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = -11.1 A, dl/dt = 100 A/μs,	-	30	45	nC	
Reverse Recovery Fall Time	ta	$T_{\rm J} = 25 \ ^{\circ}{\rm C}$	-	18	-		
Reverse Recovery Rise Time	t _b	1	_	16	_	ns	

Notes

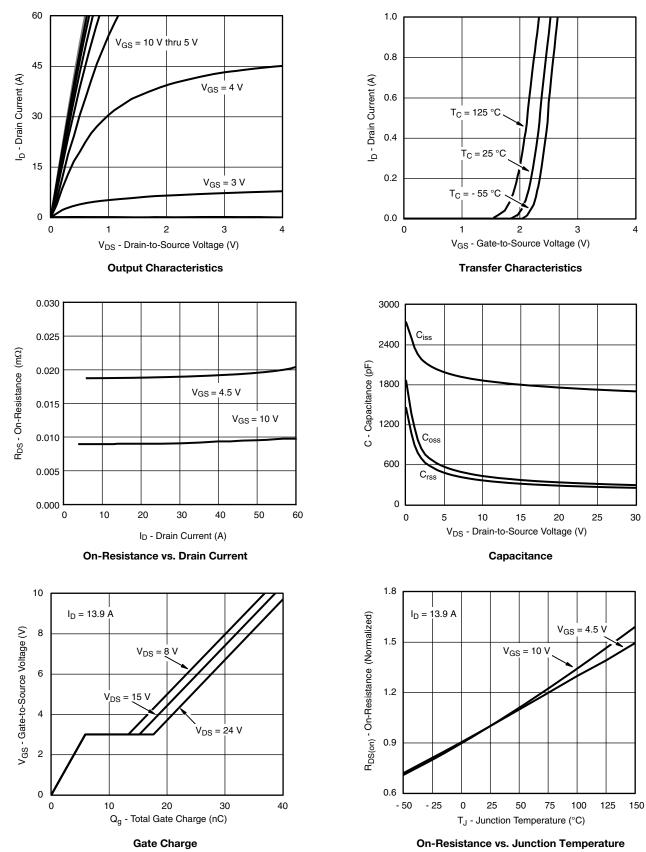
a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

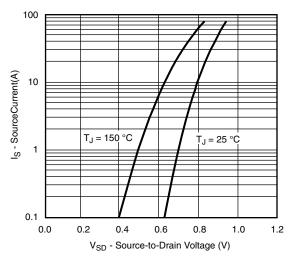
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

emi

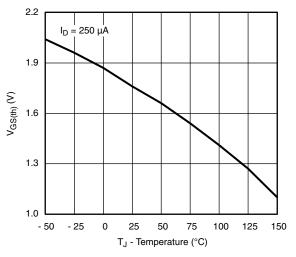




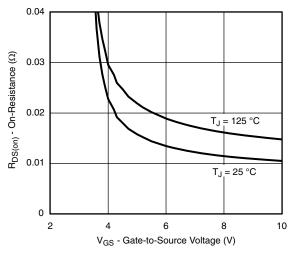




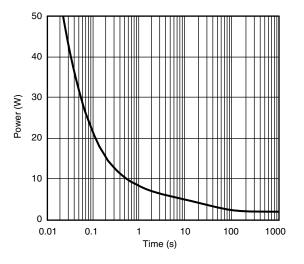




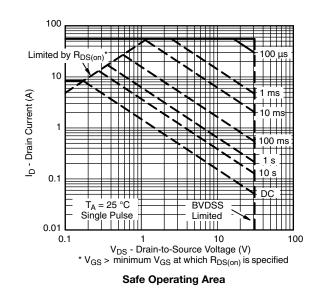




On-Resistance vs. Gate-to-Source Voltage

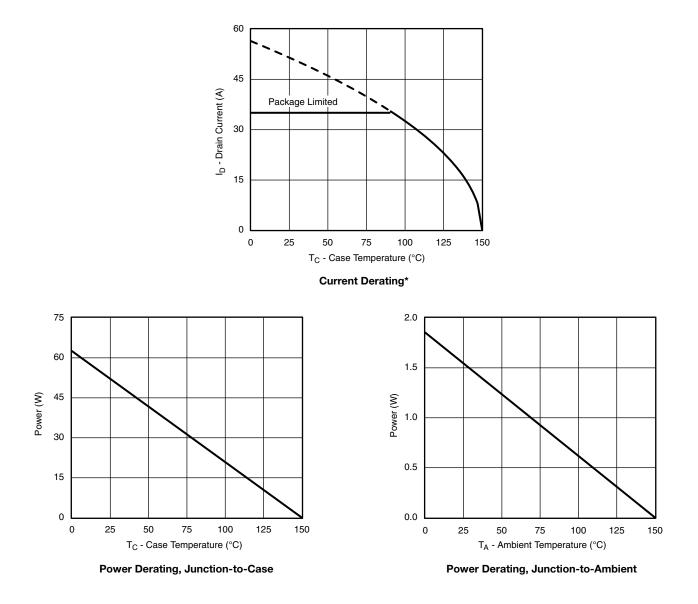


Single Pulse Power, Junction-to-Ambient



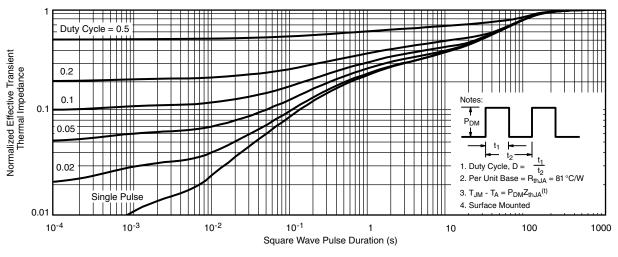
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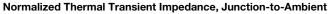


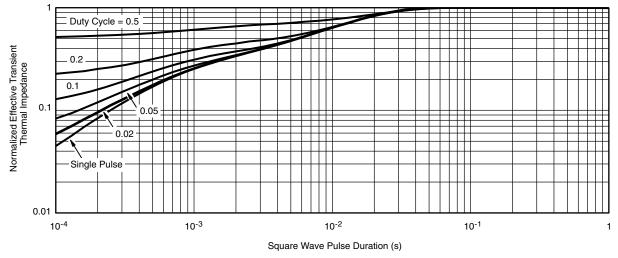


* The power dissipation P_D is based on T_J (max.) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





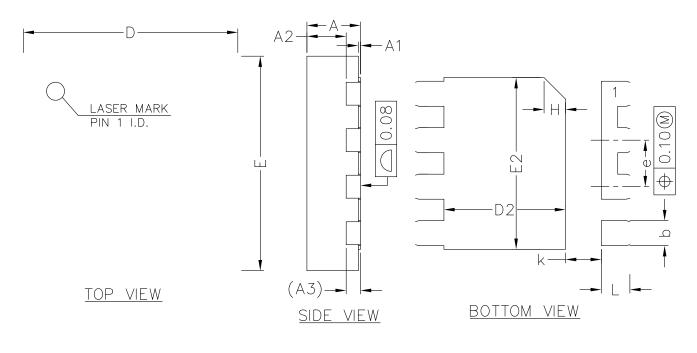




Normalized Thermal Transient Impedance, Junction-to-Case



DFN3x3 PACKAGE OUTLINE





<u>SIDE VIEW</u>

	1			
SYMBOL	MIN	NOM	MAX	
А	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
A2	0.50	0.55	0.60	
A3	0.20REF			
b	0.30	0.35	0.40	
D	2.90	3.00	3.10	
E	2.90	3.00	3.10	
D2	1.60	1.70	1.80	
E2	2.30	2.40	2.50	
е	0.55	0.65	0.75	
K	0.40	0.50	0.60	
L	0.35	0.40	0.45	

COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)



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